



# IEEE Standard Method for Measuring the Effectiveness of Electromagnetic Shielding Enclosures

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**IEEE Electromagnetic Compatibility Society**

Sponsored by the  
Standards Development Committee

299<sup>TM</sup>

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(Revision of IEEE Std 299-1997)



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**Standards Development Committee  
of the  
IEEE Electromagnetic Compatibility Society**

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**Abstract:** Uniform measurement procedures and techniques are provided for determining the effectiveness of electromagnetic shielding enclosures at frequencies from 9 kHz to 18 GHz (extendable to 50 Hz and 100 GHz, respectively) for enclosures having all dimension greater than or equal to 2.0 m. The types of enclosures covered include, but are not limited to, single-shield or double-shield structures of various construction, such as bolted demountable, welded, or integral with a building; and made of materials such as steel plate, copper or aluminum sheet, screening, hardware cloth, metal foil, or shielding fabrics.

**Keywords:** electromagnetic shielding, screened rooms, shielded enclosures, shielded rooms, shielding, shielding effectiveness

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## Introduction

This introduction is not part of IEEE Std 299-2006, IEEE Standard Method for Measuring the Effectiveness of Electromagnetic Shielding Enclosures.

This document provides a standard set of methods and procedures for determining the shielding effectiveness (SE) of shielding enclosures. The enclosures of concern include those used for testing groups of equipment, vehicles, computing systems, and smaller units whose electromagnetic (EM) emission and susceptibility require determination without disturbance from other sources. This standard incorporates the basic concepts of MIL-STD-285,<sup>a</sup> the SE measurement reference for many years, which was cancelled by the U.S. Department of Defense in 1997. Those concepts have been expanded upon to increase the applicability of the measurement techniques to enclosures having a wide variety of applications and constructed from a large number of materials with varying methods of fabrication and assembly.

The basic premise of MIL-STD-285 is still in position: the shield effect is to provide an insertion loss to outside influence. IEEE Std 299-2006 offers testing based upon the performance specifications of the shield, rather than a fixed set of parameters that may not be applicable to the shield in question. The specific test procedures and frequency ranges are selected as appropriate for the enclosure being tested. The most important factor considered during the development of this revision was the concept that measurement of EM SE is a requirement not unique to walk-in sized enclosures. There are no widely accepted standards in use to describe test methods and techniques for measuring SE of physically small enclosures. The Standards Development Committee of the IEEE Electromagnetic Compatibility Society directed the current Working Group to plan for developing new parts of IEEE Std 299 for addressing the testing of these smaller enclosures. Thus, this document will continue to provide a standardized test method for EM shielded enclosures having all dimensions greater than or equal to 2 m. New parts of IEEE Std 299 will be developed soon to address these smaller enclosures.

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## Participants

The many contributions to this standard by the members of the P299 Working Group are gratefully acknowledged. The support of the Vice Chairs, Norman Wehling (retired) and Dr. Croisant, was invaluable, as were the editing efforts of Mark Bushnell and improvements to the figures by Joseph Weibler. Professor Sarto was also extremely helpful in clarifying many of the concepts and equations.

Special appreciation is extended to Don Sweeney who served as liaison from the EMC Society Standards Development Committee and “Angel” for the project.

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## Contents

1. Overview .....	1
1.1 Scope .....	1
1.2 Purpose .....	1
1.3 Application .....	1
2. Normative references.....	2
3. Definitions.....	2
3.1 General terminology.....	2
3.2 Technical terminology.....	3
4. Preliminary procedures.....	3
4.1 Background.....	3
4.2 Test plan .....	4
4.3 Calibration .....	4
4.4 Reference level and dynamic range .....	4
4.5 Preliminary shield check procedures .....	4
4.6 Test/witness personnel.....	4
5. Detailed procedures.....	4
5.1 Background.....	4
5.2 Recommended standard measurement frequencies .....	5
5.3 Pass/fail requirements.....	6
5.4 Shielding effectiveness calculation.....	6
5.5 Preparation procedures .....	7
5.6 Low-frequency measurements (9 kHz to 20 MHz) .....	7
5.7 Resonant range measurements (20 MHz to 300 MHz).....	11
5.8 High-frequency measurements (300 MHz to 18 GHz).....	18
6. Quality assurance technical report.....	24
6.1 Abbreviated test report .....	24
6.2 Full test report.....	24
Annex A (informative) Rationale .....	26
A.1 Basis.....	26
A.2 Considerations pertinent to the objectives of 1.2.....	26
A.3 Cavity resonances .....	27
A.4 Measurement locations .....	30
A.5 Measurement equipment.....	30

Annex B (informative) Mathematical formulas.....	31
B.1 Specific mathematical formulations.....	31
B.2 Low-range (50 Hz to 20 MHz) shielding effectiveness .....	31
B.3 Resonant range (20 MHz to 300 MHz) shielding effectiveness.....	32
B.4 High-range (300 MHz to 100 GHz) shielding effectiveness.....	32
B.5 Nonlinear (logarithmic) calculations.....	32
B.6 Dynamic range considerations .....	33
Annex C (informative) Miscellaneous supporting information.....	34
C.1 Coplanar versus coaxial loops.....	34
C.2 Nonlinearity of high-permeability ferromagnetic enclosures.....	34
C.3 Selecting measurement frequencies .....	34
Annex D (informative) Guidelines for the selection of measurement techniques.....	37
D.1 Types of enclosures .....	37
D.2 Performance requirements .....	37
D.3 Equipment requirements.....	38
D.4 Regulatory agency conflicts.....	38
Annex E (informative) Preliminary measurements and repairs.....	39
E.1 Background .....	39
E.2 Frequencies for preliminary check .....	39
E.3 Preliminary check procedures .....	39

# IEEE Standard Method for Measuring the Effectiveness of Electromagnetic Shielding Enclosures

## 1. Overview

### 1.1 Scope

This standard provides uniform measurement procedures for determining the effectiveness of electromagnetic (EM) shielding enclosures at frequencies from 9 kHz to 18 GHz (extendable down to 50 Hz and up to 100 GHz).

The owner of the shielding enclosure shall provide the frequencies at which the shield will be tested, and the shielding effectiveness (SE) limits for pass/fail. This standard suggests a range of test frequencies that would provide very high confidence in the effectiveness of the shield. This standard does not define SE limits for pass or fail.

### 1.2 Purpose

The purpose of this standard is to provide the following:

- a) A standard procedure for the measurement of the effectiveness of shielded enclosures, in a broad range of radio frequencies (RFs), including a minimum set of recommended frequencies
- b) Identical procedures applicable to frequencies other than the standard set
- c) An optional measurement technique to detect the nonlinear behavior of high-permeability ferromagnetic enclosures (see Annex C)

### 1.3 Application

The measurement procedures provided in this standard apply to any enclosure having a smallest linear dimension greater than or equal to 2.0 m. Separate methods, to be provided in the future, shall be used for enclosures with any dimension smaller than 2.0 m.

In the case of enclosures that are to be used in anechoic or semianechoic applications, this procedure shall apply prior to the installation of any RF absorber materials.